Docket No.: 50090-265

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

re Application of :

Kiyotoshi UEDA, et al. :

Serial No.: 09/766,845 : Group Art Unit: 2829

Filed: January 23, 2001 : Examiner: P. Patel

For: METHOD AND APPARATUS FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUIT, AND SEMICONDUCTOR INTEGRATED CIRCUIT MANUFACTURED THEREBY

THE COMMISSIONER FOR PATENTS AND TRADEMARKS
Washington, DC 20231

Dear Sir:

Transmitted herewith is an Amendment in the above identified application.

☒ No additional fee is required.
☐ Applicant is entitled to small entity status under 37 CFR 1.27
☐ Also attached:

The fee has been calculated as shown below:

	NO. OF CLAIMS	HIGHEST PREVIOUSLY PAID FOR	EXTRA CLAIMS	RATE	FEE
Total Claims	14	20	0	$18.00 =	$0.00
Independent Claims	2	3	0	$84.00 =	$0.00
		Multiple claims newly presented			$0.00
		Fee for extension of time			$0.00
					$0.00
				Total of Above Calculations	$0.00

☐ Please charge my Deposit Account No. 500417 in the amount of $0.00. An additional copy of this transmittal sheet is submitted herewith.

☒ The Commissioner is hereby authorized to charge payment of any fees associated with this communication or credit any overpayment, to Deposit Account No. 500417, including any filing fees under 37 CFR 1.16 for presentation of extra claims and any patent application processing fees under 37 CFR 1.17.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

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